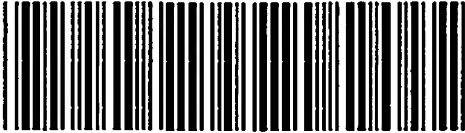


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/717,502	MIYAKAWA ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Mark Eashoo, Ph.D.	1732	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor Name Search (see search history printout)	10/1/2005	ME
EAST (US-PGPUB, USPAT, USOCR,EPO,JPO, DERWENT)- see search history printout	10/1/2005	ME